Search Notes



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Applicant(s)/Patent Under Reexamination

KWON ET AL.

Examiner

Art Unit

Ley, Francisco M

3746

SEARCHED

Class	Subclass	Date	Examiner
417	416, 417, DIG1	8/13/07	FML
252	67, 68, 69	8/13/07	FML
418	100	8/13/07	FML

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Search Notes	Date	Examiner
NPL search on Google and SCIRUS	9/04/07	FML

INTERFERENCE SEARCH

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